



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Accredited Labs dba Quality Surveillance, Inc.
1200 Yarnell Place
Oxnard, CA 93033

Fulfills the requirements of

ISO/IEC 17025:2017

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 08 January 2028

Certificate Number: AC-3452



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Accredited Labs dba Quality Surveillance, Inc.

1200 Yarnell Place
Oxnard, CA 93033
Brett Bohannon 208-860-3981

CALIBRATION

ISO/IEC 17025 Accreditation Granted: **08 January 2026**

Certificate Number: **AC-3452** Certificate Expiry Date: **08 January 2028**

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Measure ¹	(10 to 100) μ A		Comparison to Precision Multimeter
	(10 to 20) Hz	4 mA/A + 0.03 μ A	
	(20 to 45) Hz	1.5 mA/A + 0.03 μ A	
	(45 to 100) Hz	600 μ A/A + 0.03 μ A	
	100 Hz to 1 kHz	620 μ A/A + 0.03 μ A	
	(0.1 to 1) mA		
	(1 to 10) Hz	4 mA/A + 0.2 μ A	
	(10 to 40) Hz	1.5 mA/A + 0.2 μ A	
	(40 to 100) Hz	600 μ A/A + 0.2 μ A	
	100 Hz to 1 kHz	330 μ A/A + 0.2 μ A	
	(1 to 20) kHz	600 μ A/A + 0.2 μ A	
	(20 to 50) kHz	4 mA/A + 0.4 μ A	
	(50 to 100) kHz	5.5 mA/A + 1.5 μ A	
	(1 to 10) mA		
	(1 to 10) Hz	4 mA/A + 2 μ A	
	(10 to 40) Hz	1.5 mA/A + 2 μ A	
	(40 to 100) Hz	600 μ A/A + 2 μ A	
	100 Hz to 1 kHz	320 μ A/A + 2 μ A	
	(1 to 20) kHz	600 μ A/A + 2 μ A	
	(20 to 50) kHz	4 mA/A + 4 μ A	
	(50 to 100) kHz	5.5 mA/A + 15 μ A	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Measure ¹	(10 to 100) mA		Comparison to Precision Multimeter
	(1 to 10) Hz	4 mA/A + 20 μ A	
	(10 to 40) Hz	1.5 mA/A + 20 μ A	
	(40 to 100) Hz	600 μ A/A + 20 μ A	
	100 Hz to 1 kHz	320 μ A/A + 20 μ A	
	(1 to 20) kHz	600 μ A/A + 20 μ A	
	(20 to 50) kHz	4 mA/A + 40 μ A	
	(50 to 100) kHz	5.5 mA/A + 150 μ A	
	(0.1 to 1 A)		
	(1 to 10) Hz	4 mA/A + 200 μ A	
	(10 to 40) Hz	1.6 mA/A + 200 μ A	
	(40 to 100) Hz	800 μ A/A + 200 μ A	
	100 Hz to 1 kHz	1 mA/A + 200 μ A	
	(1 to 20) kHz	3 mA/A + 200 μ A	
	(20 to 50) kHz	9.6 mA/A + 400 μ A	
AC Current – Source	(29 to 330) μ A		Comparisons performed with a Multifunction Calibrator
	(10 to 20) Hz	2 mA/A + 0.1 μ A	
	(20 to 45) Hz	1.5 mA/A + 0.1 μ A	
	45 Hz to 1 kHz	1.25 mA/A + 0.1 μ A	
	(1 to 5) kHz	3 mA/A + 0.15 μ A	
	(5 to 10) kHz	8 mA/A + 0.2 μ A	
	(10 to 30) kHz	16 mA/A + 0.4 μ A	
	(0.33 to 3.3) mA		
	(10 to 20) Hz	2 mA/A + 0.15 μ A	
	(20 to 45) Hz	1.25 mA/A + 0.15 μ A	
	45 Hz to 1 kHz	1 mA/A + 0.15 μ A	
	(1 to 5) kHz	2 mA/A + 0.2 μ A	
	(5 to 10) kHz	5 mA/A + 0.3 μ A	
	(10 to 30) kHz	10 mA/A + 0.6 μ A	
	(3.3 to 33) mA		
	(10 to 20) Hz	1.8 mA/A + 2 μ A	
	(20 to 45) Hz	0.9 mA/A + 2 μ A	
	45 Hz to 1 kHz	0.4 mA/A + 2 μ A	
	(1 to 5) kHz	0.8 mA/A + 2 μ A	
	(5 to 10) kHz	2 mA/A + 3 μ A	
	(10 to 30) kHz	4 mA/A + 4 μ A	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source	(33 to 330) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	1.8 mA/A + 20 μ A 0.9 mA/A + 20 μ A 0.4 mA/A + 20 μ A 1 mA/A + 50 μ A 2 mA/A + 0.1 mA 4 mA/A + 0.2 mA	Comparisons performed with a Multifunction Calibrator
AC Current – Source (Current Clamp-on Meters)	(20 to 1 000) A (45 to 65) Hz (65 to 440) Hz	7.2 mA/A + 0.58 A 7.7 mA/A + 0.58 A	Comparisons performed with a Multifunction Calibrator and using 50-turn Coil
AC Voltage – Measure ¹	(1 to 10) mV (10 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (10 to 100) mV (10 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 4) MHz (4 to 8) MHz (8 to 10) MHz (0.1 to 1) V (10 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 4) MHz (4 to 8) MHz (8 to 10) MHz	0.34 mV/V + 3.5 μ V 0.23 mV/V + 1.3 μ V 0.34 mV/V + 1.3 μ V 1.2 mV/V + 1.3 μ V 5.8 mV/V + 1.3 μ V 49.2 mV/V + 2.3 μ V 80 μ V/V + 4 μ V 90 μ V/V + 2 μ V 190 μ V/V + 2 μ V 300 μ V/V + 2 μ V 870 μ V/V + 2 μ V 3.1 mV/V + 10 μ V 11 mV/V + 10 μ V 40 mV/V + 70 μ V 40 mV/V + 80 μ V 150 mV/V + 1000 μ V 70 μ V/V + 40 μ V 74 μ V/V + 20 μ V 150 μ V/V + 20 μ V 310 μ V/V + 20 μ V 810 μ V/V + 20 μ V 3 mV/V + 0.1 mV 9.9 mV/V + 0.1 mV 40 mV/V + 0.7 mV 40 mV/V + 0.8 mV 150 mV/V + 1 mV	Comparison to Precision Multimeter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	(1 to 10) V		Comparison to Precision Multimeter
	(10 to 40) Hz	80 $\mu\text{V/V} + 400 \mu\text{V}$	
	40 Hz to 1 kHz	73 $\mu\text{V/V} + 200 \mu\text{V}$	
	(1 to 20) kHz	150 $\mu\text{V/V} + 200 \mu\text{V}$	
	(20 to 50) kHz	310 $\mu\text{V/V} + 200 \mu\text{V}$	
	(50 to 100) kHz	810 $\mu\text{V/V} + 200 \mu\text{V}$	
	(100 to 300) kHz	3 mV/V + 1 mV	
	300 kHz to 1 MHz	9.9 mV/V + 1 mV	
	(1 to 4) MHz	41 mV/V + 7 mV	
	(4 to 8) MHz	41 mV/V + 8 mV	
	(8 to 10) MHz	150 mV/V + 10 mV	
	(10 to 100) V		
	(10 to 40) Hz	200 $\mu\text{V/V} + 4 \text{ mV}$	
	40 Hz to 1 kHz	210 $\mu\text{V/V} + 2 \text{ mV}$	
	(1 to 20) kHz	210 mV/V + 2 mV	
	(20 to 50) kHz	360 $\mu\text{V/V} + 2 \text{ mV}$	
	(50 to 100) kHz	1.2 mV/V + 2 mV	
	(100 to 700) V		
	(10 to 40) Hz	590 $\mu\text{V/V} + 40 \text{ mV}$	
	40 Hz to 1 kHz	410 $\mu\text{V/V} + 20 \text{ mV}$	
	(1 to 20) kHz	600 $\mu\text{V/V} + 20 \text{ mV}$	
	(20 to 50) kHz	1.2 mV/V + 20 mV	
	(50 to 100) kHz	3 mV/V + 20 mV	
Capacitance – Source	(0.22 to 1.1) nF	0.5 % of reading + 10 pF	Comparisons performed with a Multifunction Calibrator
	(1.1 to 3.3) nF	0.5 % of reading + 10 pF	
	(3.3 to 110) nF	0.25 % of reading + 10 pF	
	(110 to 330) nF	0.25 % of reading + 30 pF	
	(0.33 to 1.1) μF	0.25 % of reading + 1 nF	
	(1.1 to 3.3) μF	0.25 % of reading + 3 nF	
	(3.3 to 11) μF	0.25 % of reading + 10 nF	
	(11 to 33) μF	0.4 % of reading + 30 nF	
	(33 to 110) μF	0.45 % of reading + 100 nF	
	(110 to 330) μF	0.45 % of reading + 300 nF	
	(0.33 to 1.1) mF	0.45 % of reading + 1 μF	
	(1.1 to 3.3) mF	0.45 % of reading + 3 μF	
	(3.3 to 11) mF	0.45 % of reading + 10 μF	
	(11 to 33) mF	0.75 % of reading + 30 μF	
	(33 to 110) mF	1.1 % of reading + 100 μF	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Current – Measure ¹	(10 to 100) μ A (0.1 to 1) mA (1 to 10) mA (10 to 100) mA (0.1 to 1) A	51 μ A/A + 1.6 nA 51 μ A/A + 10 nA 51 μ A/A + 0.1 μ A 81 μ A/A + 1 μ A 0.23 mA/A + 20 μ A	Comparison to Precision Multimeter
DC Current – Source	(0 to 330) μ A (0 to 3.3) mA (3.3 to 33) mA (33 to 330) mA 330 mA to 1.1 A (1.1 to 3) A (3 to 11) A (11 to 20.5) A	150 μ A/A + 0.02 μ A 100 μ A/A + 0.05 μ A 100 μ A/A + 0.25 μ A 100 μ A/A + 2.5 μ A 200 μ A/A + 40 μ A 380 μ A/A + 40 μ A 500 μ A/A + 500 μ A 1000 μ A/A + 750 μ A	Comparisons performed with a Multifunction Calibrator
DC Current – Source (Current Clamp-on Meters)	20 A to 1 000 A	8.7 mA/A + 0.58 A	Comparisons performed with a Multifunction Calibrator and using 50-turn Coil
DC Resistance – Measure ¹	(1 to 10) Ω (10 to 100) Ω 100 Ω to 1 k Ω (1 to 10) k Ω (10 to 100) k Ω 100 k Ω to 1 M Ω (1 to 10) M Ω (10 to 100) M Ω 100 M Ω to 1 G Ω	18.2 $\mu\Omega/\Omega$ + 60 $\mu\Omega$ 14.9 $\mu\Omega/\Omega$ + 0.57 m Ω 13.2 $\mu\Omega/\Omega$ + 0.5 m Ω 13 $\mu\Omega/\Omega$ + 6 m Ω 13 $\mu\Omega/\Omega$ + 60 m Ω 18.3 $\mu\Omega/\Omega$ + 2.3 Ω 58.1 $\mu\Omega/\Omega$ + 0.11 k Ω 0.56 m Ω/Ω + 1 k Ω 5 m Ω/Ω + 10 k Ω	Comparison to Precision Multimeter
Resistance – Source (Simulation) *This is 1hr and $\pm 1^\circ\text{C}$ since zero cal*	(0 to 11) Ω (11 to 33) Ω (33 to 110) Ω 110 Ω to 1.1 k Ω (1.1 to 11) k Ω (11 to 110) k Ω 110 k Ω to 1.1 M Ω (1.1 to 3.3) M Ω (3.3 to 11) M Ω (11 to 33) M Ω (33 to 110) M Ω (110 to 330) M Ω 330 M Ω to 1.1 G Ω	40 $\mu\Omega/\Omega$ + 1 m Ω 30 $\mu\Omega/\Omega$ + 1.5 m Ω 28 $\mu\Omega/\Omega$ + 1.4 m Ω 28 $\mu\Omega/\Omega$ + 2 m Ω 28 $\mu\Omega/\Omega$ + 20 m Ω 28 $\mu\Omega/\Omega$ + 200 m Ω 32 $\mu\Omega/\Omega$ + 2 Ω 60 $\mu\Omega/\Omega$ + 30 Ω 130 $\mu\Omega/\Omega$ + 50 Ω 250 $\mu\Omega/\Omega$ + 2.5 k Ω 0.5 m Ω/Ω + 3 k Ω 3 m Ω/Ω + 0.1 M Ω 15 m Ω/Ω + 0.5 M Ω	Comparisons performed with a Multifunction Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
RTD Resistance Simulation	Pt 385, 100 Ω		Comparisons performed with Multifunction Calibrator and Electronic Indicator
	(-200 to 0) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(0 to 100) $^{\circ}\text{C}$	0.07 $^{\circ}\text{C}$	
	(100 to 300) $^{\circ}\text{C}$	0.09 $^{\circ}\text{C}$	
	(300 to 400) $^{\circ}\text{C}$	0.10 $^{\circ}\text{C}$	
	(400 to 630) $^{\circ}\text{C}$	0.12 $^{\circ}\text{C}$	
	(630 to 800) $^{\circ}\text{C}$	0.23 $^{\circ}\text{C}$	
	Pt 3926, 100 Ω		
	(-200 to 0) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(0 to 100) $^{\circ}\text{C}$	0.07 $^{\circ}\text{C}$	
	(100 to 300) $^{\circ}\text{C}$	0.09 $^{\circ}\text{C}$	
	(300 to 400) $^{\circ}\text{C}$	0.10 $^{\circ}\text{C}$	
	(400 to 630) $^{\circ}\text{C}$	0.12 $^{\circ}\text{C}$	
	Pt 3926, 100 Ω		
	(-200 to -190) $^{\circ}\text{C}$	0.25 $^{\circ}\text{C}$	
	(-190 to -80) $^{\circ}\text{C}$	0.04 $^{\circ}\text{C}$	
	(-80 to 0) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(0 to 100) $^{\circ}\text{C}$	0.06 $^{\circ}\text{C}$	
	(100 to 260) $^{\circ}\text{C}$	0.07 $^{\circ}\text{C}$	
	(260 to 300) $^{\circ}\text{C}$	0.08 $^{\circ}\text{C}$	
	(300 to 400) $^{\circ}\text{C}$	0.09 $^{\circ}\text{C}$	
	(400 to 600) $^{\circ}\text{C}$	0.10 $^{\circ}\text{C}$	
	(600 to 630) $^{\circ}\text{C}$	0.23 $^{\circ}\text{C}$	
	Pt 385, 200 Ω		
	(-200 to 100) $^{\circ}\text{C}$	0.04 $^{\circ}\text{C}$	
	(100 to 260) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(260 to 300) $^{\circ}\text{C}$	0.12 $^{\circ}\text{C}$	
	(300 to 400) $^{\circ}\text{C}$	0.13 $^{\circ}\text{C}$	
	(400 to 600) $^{\circ}\text{C}$	0.14 $^{\circ}\text{C}$	
	(600 to 630) $^{\circ}\text{C}$	0.16 $^{\circ}\text{C}$	
	Pt 385, 500 Ω		
	(-200 to -80) $^{\circ}\text{C}$	0.04 $^{\circ}\text{C}$	
	(-80 to 100) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(100 to 260) $^{\circ}\text{C}$	0.06 $^{\circ}\text{C}$	
	(260 to 400) $^{\circ}\text{C}$	0.08 $^{\circ}\text{C}$	
	(400 to 600) $^{\circ}\text{C}$	0.09 $^{\circ}\text{C}$	
	(600 to 630) $^{\circ}\text{C}$	0.11 $^{\circ}\text{C}$	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
RTD Resistance Simulation (continued)	PtNi 385, 120 Ω (Ni 120)		Comparisons performed with Multifunction Calibrator and Electronic Indicator
	(-80 to 100) $^{\circ}\text{C}$	0.08 $^{\circ}\text{C}$	
	(100 to 260) $^{\circ}\text{C}$	0.14 $^{\circ}\text{C}$	
	Pt 385, 1 000 Ω		
	(-200 to 0) $^{\circ}\text{C}$	0.03 $^{\circ}\text{C}$	
	(0 to 100) $^{\circ}\text{C}$	0.04 $^{\circ}\text{C}$	
	(100 to 260) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(260 to 300) $^{\circ}\text{C}$	0.06 $^{\circ}\text{C}$	
	(300 to 600) $^{\circ}\text{C}$	0.07 $^{\circ}\text{C}$	
DC Voltage – Measure ¹	(600 to 630) $^{\circ}\text{C}$	0.23 $^{\circ}\text{C}$	Comparison to Precision Multimeter
	Cu 427, 10 Ω		
	(-100 to 0) $^{\circ}\text{C}$	0.3 $^{\circ}\text{C}$	
	(10 to 100) mV	18 $\mu\text{V/V} + 0.3 \mu\text{V}$	
	(0.1 to 1) V	8.5 $\mu\text{V/V} + 0.3 \mu\text{V}$	
DC Voltage – Source	(1 to 10) V	8.2 $\mu\text{V/V} + 0.5 \mu\text{V}$	Comparisons performed with a Multifunction Calibrator
	(10 to 100) V	11 $\mu\text{V/V} + 30 \mu\text{V}$	
	(100 to 1 000) V	11 $\mu\text{V/V} + 100 \mu\text{V}$	
	(0 to 330) mV	20 $\mu\text{V/V} + 1 \mu\text{V}$	
	330 mV to 3.3 V	11 $\mu\text{V/V} + 2 \mu\text{V}$	
Oscilloscopes	(3.3 to 33) V	12 $\mu\text{V/V} + 20 \mu\text{V}$	Comparisons performed with a Multifunction Calibrator
	(33 to 330) V	18 $\mu\text{V/V} + 150 \mu\text{V}$	
	(330 to 1 020) V	18 $\mu\text{V/V} + 1.5 \text{ mV}$	
	Amplitude – DC		
	into 50 Ω Load	1 mV to 6.6 V	
	into 1 M Ω Load	1 mV to 130 V	
	Amplitude – Square Wave		
	10 Hz to kHz		
	into 50 Ω Load	1 mVp-p to 6.6 Vp-p	
	into 1 M Ω Load	1 mVp-p to 130 Vp-p	
	Amplitude –		
	Leveled Sine Wave Flatness (Relative to 50 kHz)		
	5 mV to 5.5 V		
	50 kHz to 100 MHz	1.5 % + 100 μV	
	(100 to 300) MHz	2 % + 100 μV	
	(300 to 600) MHz	4 % + 100 μV	
	600 MHz to 1.1 GHz	5 % + 100 μV	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Oscilloscopes Amplitude – Leveled Sine (Absolute Amplitude)	4 mV to 3.5 V 600 MHz to 1.1 GHz	41 mV/V + 0.1 mV	Comparisons performed with a Multifunction Calibrator
Time Marker into 50 Ω Load (Spike, Square Wave Spike, Square, 20 % Pulse Spike or Square Wave Square or Sine Wave)	5 mV to 5.5 V 50 kHz Reference 50 ms to 5 s 100 ns to 20 ms (20 to 50) ns 10 ns (1 to 5) ns	1 5 mV/V + 0.3 mV (25 + 1 000t) μ s/s 2 μ s/s 2 μ s/s 2 μ s/s 2 μ s/s	
Edge Characteristics: (into 50 Ω) Rise Time	<300 ps	7.5 ns	

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Gage Blocks ²	(0.1 to 0.95) in (1 to 4) in	5 μ in (2.7 + 2.3L) μ in	Comparison to Mahr Federal 130B-16 Gage Block Comparator, Master Gage Blocks
Height Master ²	(1 to 4) in (4 to 12) in (12 to 24) in	(16 + 4L) μ in (42 + 3.6L) μ in (90 + 5L) μ in	Comparison to Gage Blocks
Cylindrical Plugs/Pins	(0.01 to 1) in	14 μ in	Direct Measure using Mahr 828 Universal Length Measuring Machine
Calipers ^{1,2}	(0.1 to 4) in (4 to 20) in (20 to 40) in	410 μ in (400 + 2.7L) μ in (370 + 4L) μ in	Comparison to Gage Blocks
Height Gages ^{1,2}	(0.1 to 4) in (4 to 20) in (20 to 40) in	260 μ in (240 + 4L) μ in (220 to 5L) μ in	Comparison to Gage Blocks, Surface Plate
Drop Indicator ^{1,2}	(0.000 5 to 2) in	(41 + 3L) μ in	Comparison to Gage Blocks

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Depth Micrometers ^{1,2}	(0.1 to 1) in (1 to 4) in (4 to 12) in	(40 + 1.1L) μ in (37 + 3.7L) μ in (14 + 9.7L) μ in	Comparison to Gage Blocks, Surface Plate
Outside Micrometers ^{1,2}	(0.1 to 1) in (1 to 4) in (4 to 20) in (20 to 40) in	(40 + 1.1L) μ in (37 + 3.7L) μ in (24 + 9.3L) μ in (70 + 7L) μ in	Comparison to Gage Blocks
High Resolution Outside Micrometers ¹ (Super Micrometer)	(0.1 to 1) in	(9 + 4L) μ in	Comparison to Gage Blocks

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Pressure Gages ¹	(-30 to 0) inHg (0 to 15) psig	0.018 inHg 0.012 psi	Comparison to Ruska 6220-05A Portable Pressure Gage
Pressure Gages ¹	(-29.5 to -1) inHg (0.5 to 5) psig	0.011 inHg (0.001 5 + 0.013%) psig	Comparison to Heise HQS-2/FM Pressure Sensor
Pressure Gages ¹	(1 to 21) psig (21 to 300) psig	0.0087 psi (0.002 6 + 0.029%) psi	Comparison to Ametek RK-300 Deadweight Tester
Pressure Gages ¹	(50 to 400) psig (400 to 2 400) psig	(0.13 + 0.002 4%) psig (0.053 + 0.022%) psig	Ruska 2400L Deadweight Tester
Pressure Gages ¹	(200 to 2 000) psig (2 000 to 12 000) psig	(0.073 + 0.004 8%) psig (0.17 + 0.017%) psig	Ruska 2400H Deadweight Tester
Torque Wrenches/Drivers ¹	(5 to 100) lbf·in (100 to 300) lbf·in (300 to 1 800) lbf·in (150 to 250) lbf·ft	0.93% of Reading 0.89% of Reading 0.59% of Reading 0.71% of Reading	Comparison to Sturtevant-Richmont System 5 with Torque Transducers

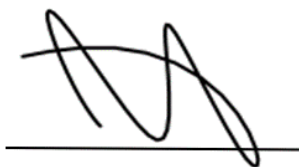
Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Relative Humidity Indicators/Recorders ^{1,3}	20 °C 33.1 %RH 75.5 %RH 25 °C 32.8 %RH 75.3 %RH	1 %RH 1.5 %RH 1.1 %RH 1.7 %RH	Comparison to Sodium Chloride and Magnesium Chloride Reference Salt Solutions and Vaisala.

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. L = length in inches.
3. Unless otherwise specified in the far-right column, the calibration procedure utilized by the laboratory was internally developed.



Jason Stine, Vice President